

ROHS

Features

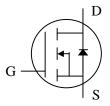
- Advanced Super Trench technology
- · Low Gate Charge.
- · Low On-Resistance
- · Low Reverse transfer capacitances
- Fast Switching
- · Reliable and Rugged
- Fully lead (Pb)-free device
- 100% avalanche energy Test



TOLLA View

Applications

- Power Management.
- · PWM Application.
- · Load Switching.



Schematic Diagram

Product Summary

Parameter	Value	Unit
V _{DS}	30	V
In @ V _{GS} = 10V	384	Α
R _{DS(ON)} (typ.) @ V _{GS} =10V	0.50	mΩ





Order information

Product Name	Package	Media	Q'ty (pcs)
XPXGL36068LAC	TOLLA	Reel&Tape	2000



Absolute maximum ratings (at T_A = 25°C, unless otherwise specified)

Symbol	Parameter		Rating	Unit
VDS	Drain-Source Voltage		30	V
Vgs	Gate-Source Voltage		±20	V
ΙD	Drain Current -Continuous ①	Tc= 25°C	384	Α
l ID		Tc= 100°C	272	Α
I _{DM}	Drain Current -Pulsed ① Tc= 25°C		1260	Α
D-	PD Maximum Power Dissipation	Tc= 25°C	250	W
PD		Tc= 100°C	125	W
RthJ-C	Thermal Resistance-Junction to Case	Steady State	0.60	°C/W
RthJ-A	Thermal Resistance-Junction to Ambient ③	Steady State	50	°C/W
las	Avalanche Energy, Single pulse ② ④	L=0.5mH	58	Α
Eas	Avalanche Energy, Single pulse ② ④	L=0.5mH	841	mJ
Tstg	Storage Temperature		-55 to175	°C
Tj	Maximum Junction Temperature		175	°C

Note:

- ①,Pulse width limited by maximum junction temperature.
- ②,UIS tested and pulse width limited by maximum junction temperature 175°C (initial temperature Tj=25°C).
- ③,Surface mounted on 1in² pad area, steady state t = 999s.
- 4, EAS Condition :Tj=25 $^{\circ}$ C,VD=15V VG=10V,L=0.5mH,Rg=25 Ω .



Electrical Characteristics (Tc=25°C unless otherwise noted)

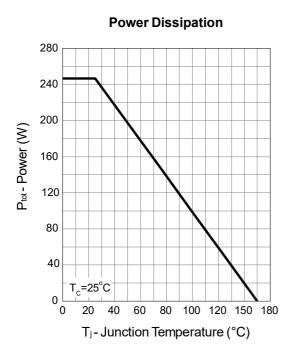
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
Off Charac	teristics	•	•		•	
V(BR)DSS	Drain-Source Breakdown Voltage	V _G s=0V I _D =250μA	30	-	-	V
lane	Zoro Coto Voltago Drain Current	V _{DS} =24V,V _{GS} =0V,Tj=25°C	-	_	1	μΑ
IDSS	Zero Gate Voltage Drain Current	V _{DS} =24V,V _{GS} =0V,Tj=85°C	-	-	30	μA
Igss	Gate-Body Leakage Current	Vgs=±20V,Vps=0V	-	-	±100	nA
On Charac	teristics					
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250µA	1.0	1.7	2.5	V
D	Drain-Source On-State Resistance (1)	Vgs=10V, ID=50A	-	0.5	0.83	mΩ
Rds(on)		Vgs=4.5V, Ip=50A	-	0.8	1.16	mΩ
Dynamic C	haracteristics (2)	_	•		•	
Rg	Input resistance	V _{DS} =V _{GS} =0V, f=1.0MHz	-	1.2	-	Ω
Clss	Input Capacitance	-V _{DS} =15V, V _{GS} =0V, -f=1.0MHz	-	9862		PF
Coss	Output Capacitance		-	3910	-	PF
Crss	Reverse Transfer Capacitance		-	415	-	PF
td(on)	Turn-on Delay Time		-	32	-	nS
tr	Turn-on Rise Time	V _{DD} =15V, I _D =1A,	-	12	-	nS
td(off)	Turn-Off Delay Time	V _{GEN} =10V, R _G =1.0Ω.	-	130	-	nS
tf	Turn-Off Fall Time	1.012.	-	36	-	nS
Qg	Total Gate Charge	V _{DS} =15V, I _D =50A, V _{GS} =10V.	-	105	-	nC
Qgs	Gate-Source Charge		-	15	-	nC
Qgd	Gate-Drain Charge		-	29	-	nC
Drain-Sour	ce Diode Characteristics					
Is	Maximun Body-Diode Continuous Current		-	384	-	Α
lsм	Maximun Body-Diode Pulsed Current		-	1260	-	Α
VsD	Diode Forward Voltage (1)	Vgs=0V,Is=30A	-	0.78	1.3	V
t _{rr}	Reverse Recovery Time	I.—EOA dia/dia 4000//	-	50	-	ns
Qrr	Reverse Recovery Charge	Is=50A, dls/dt=100A/μs	-	75	-	nC

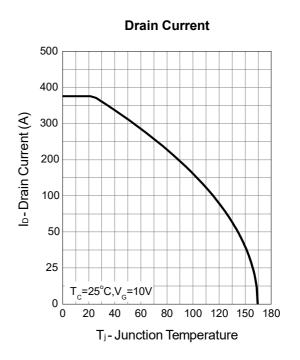
Note:

- (1): Pulse test ; pulse width≤300µs, duty cycle≤2%.
- (2): Guaranteed by design, not subject to production testing.

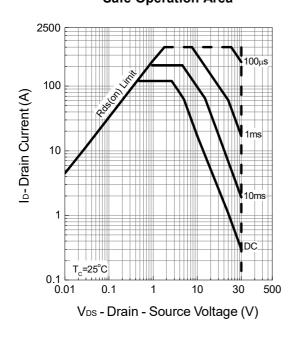


Typical Operating Characteristics

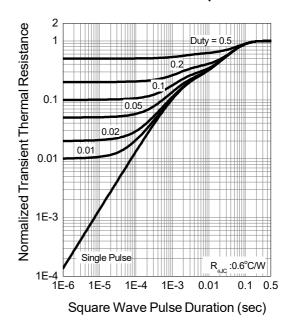




Safe Operation Area



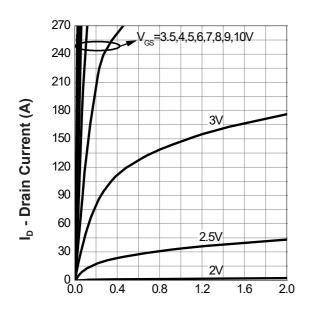
Thermal Transient Impedance





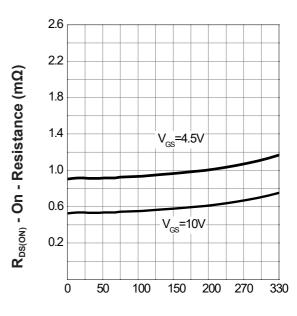
Typical Operating Characteristics

Output Characteristics



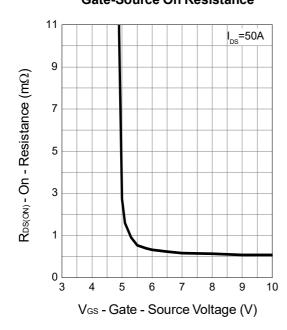
V_{DS} - Drain - Source Voltage (V)

Drain-Source On Resistance

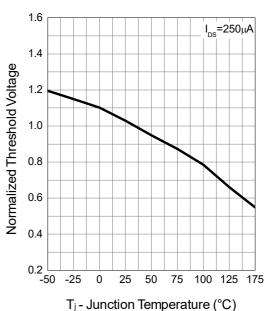


I_D - Drain Current (A)

Gate-Source On Resistance



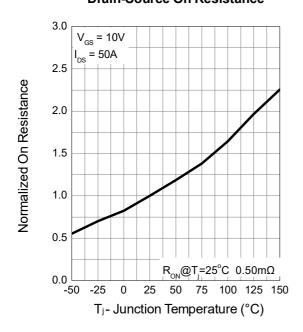
Gate Threshold Voltage



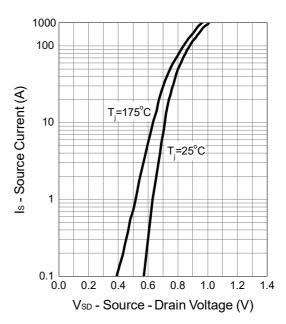


Typical Operating Characteristics

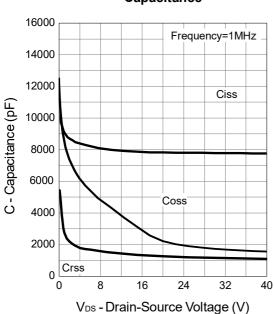
Drain-Source On Resistance



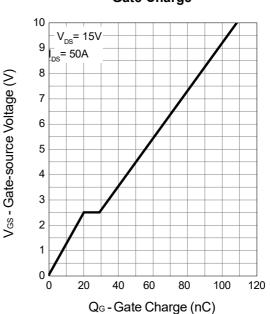
Source-Drain Diode Forward



Capacitance

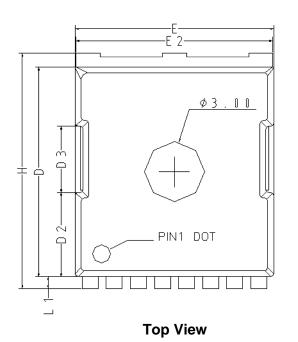


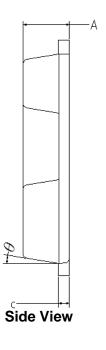
Gate Charge

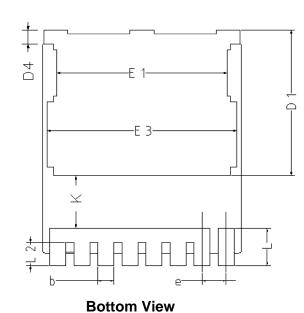




TOLLA

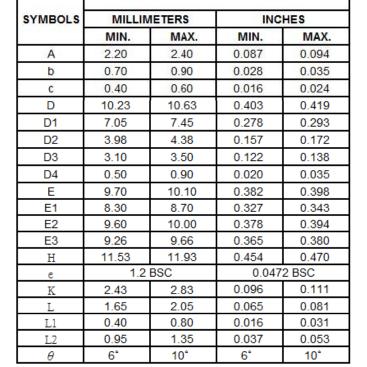


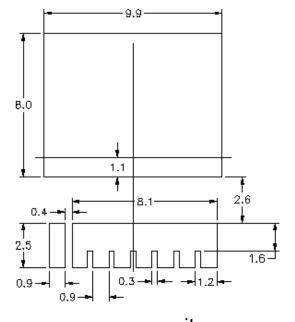




Side View

RECOMMENDED LAND PATTERN





unit:mm



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃±5℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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